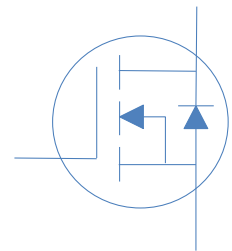


## 250V N-Ch Power MOSFET

$V_{DS}$	250	V
$R_{DS(on),typ}$	8.5	m
$I_D$ (Silicon Limited)	164	A



Part Number	Package	Marking
HG3P095N25S	TO-3P	G3P095N25S

### Absolute Maximum Ratings at $T_J=25$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	$I_D$	$T_C=25$	164	A
		$T_C=100$	116	
Drain to Source Voltage	$V_{DS}$	-	250	V
Gate to Source Voltage	$V_{GS}$	-	$\pm 20$	V
Pulsed Drain Current	$I_{DM}$	-	580	A
Avalanche Energy, Single Pulse	$E_{AS}$	$L=0.4mH, T_C=25$	180	mJ
Power Dissipation	$P_D$	$T_C=25$	600	W
Operating and Storage Temperature	$T_J, T_{stg}$	-	-55 to 175	

### Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	$R_{JC}$	0.25	$^{\circ}W$
Thermal Resistance Junction-Ambient	$R_{JA}$	40	$^{\circ}W$

## Electrical Characteristics at $T_J=25$ (unless otherwise specified)

### Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250 A$	250	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250 A$	2	2.9	4	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{GS}=0V, V_{DS}=200V, T_J=25$	-	-	1	A
		$V_{GS}=0V, V_{DS}=200V, T_J=100$	-	-	100	
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	8.5	10	m
Transconductance	$g_{fs}$	$V_{DS}=5V, I_D=20A$	-	84	-	S
Gate Resistance	$R_G$	$V_{GS}=0V, V_{DS}$ Open, $f=1MHz$	-	1.9	-	

### Dynamic Characteristics

Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=100V, f=1MHz$	-	9900	-	pF
Output Capacitance	$C_{oss}$		-	696	-	
Reverse Transfer Capacitance	$C_{rss}$		-	14	-	
Total Gate Charge	$Q_g$	$V_{DD}=125V, I_D=20A, V_{GS}=10V$	-	116	-	nC
Gate to Source Charge	$Q_{gs}$		-	36	-	
Gate to Drain (Miller) Charge	$Q_{gd}$		-	12	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=125V, I_D=20A, V_{GS}=10V, R_G=10 \Omega$	-	34	-	ns
Rise time	$t_r$		-	44	-	
Turn off Delay Time	$t_{d(off)}$		-	76	-	
Fall Time	$t_f$		-	22	-	

### Reverse Diode Characteristics

Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_F=20A$	-	0.9	-	V
Reverse Recovery Time	$t_{rr}$	$V_R=125V, I_F=20A, di_F/dt=100A/\mu s$	-	336	-	ns
Reverse Recovery Charge	$Q_{rr}$		-	1680	-	nC



Figure 3. On-Resistance vs. Drain Current and Gate Voltage

Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

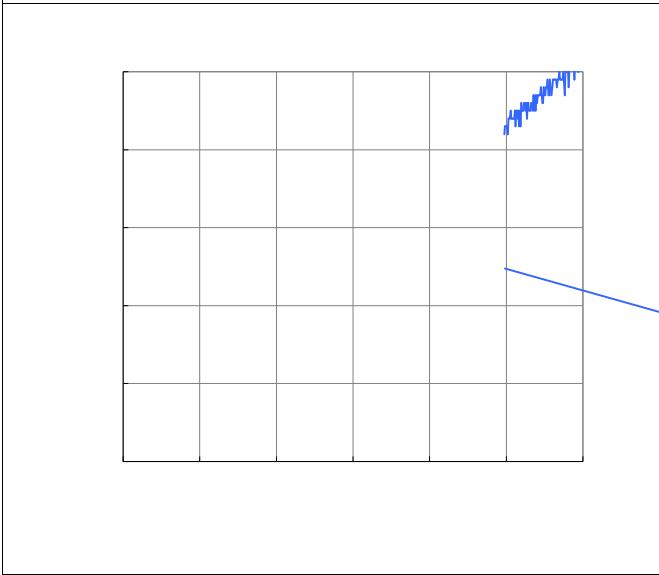


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

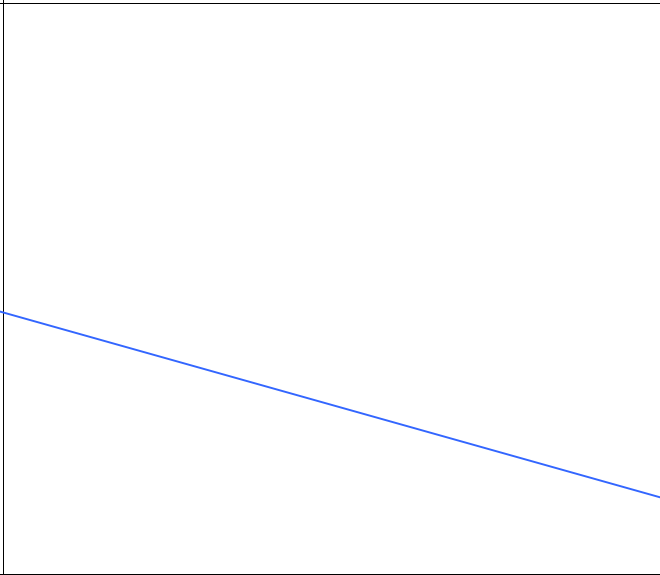


Figure 9. Maximum Safe Operating Area

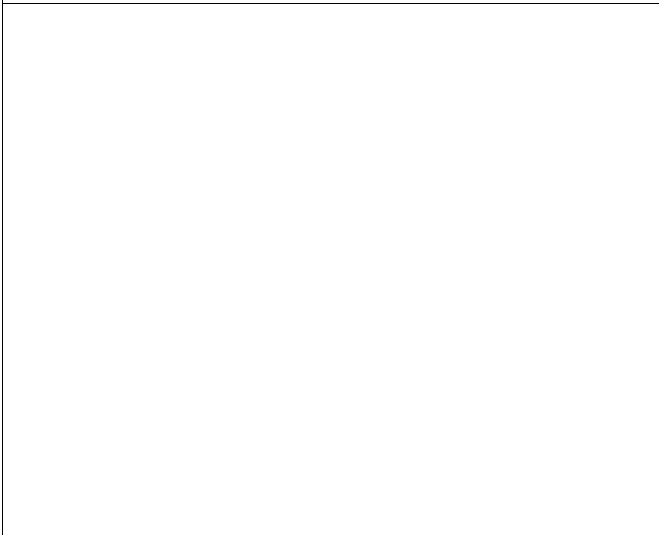


Figure 10. Maximum Drain Current vs. Case Temperature

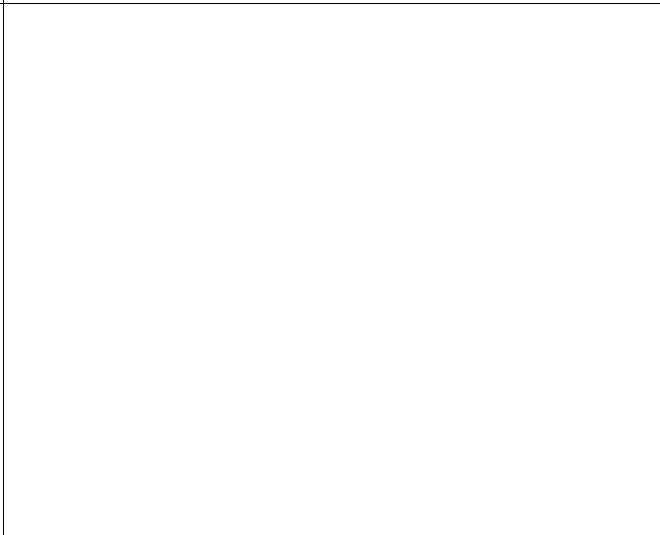
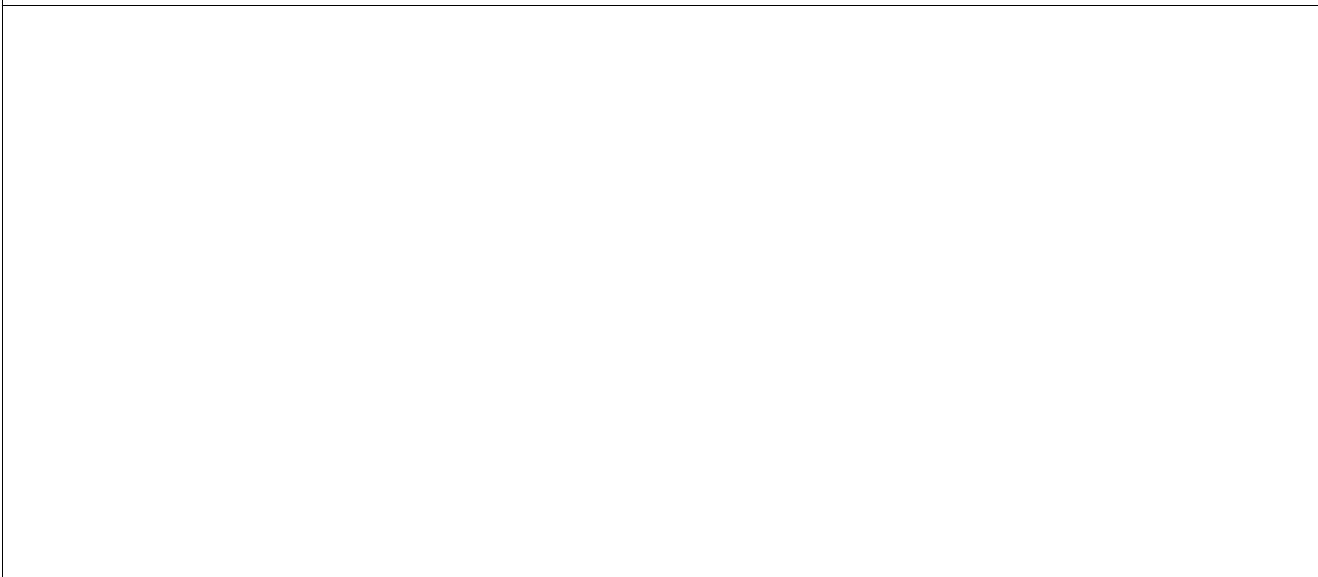
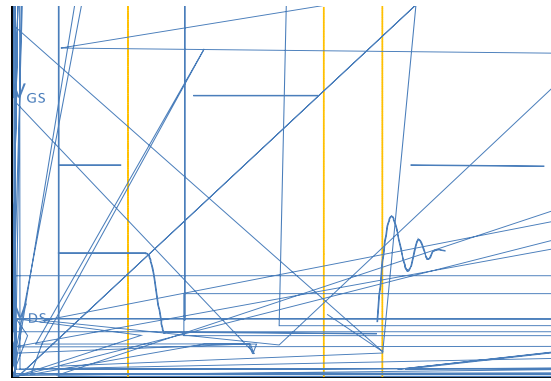
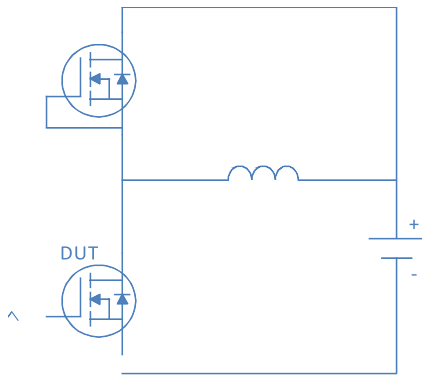


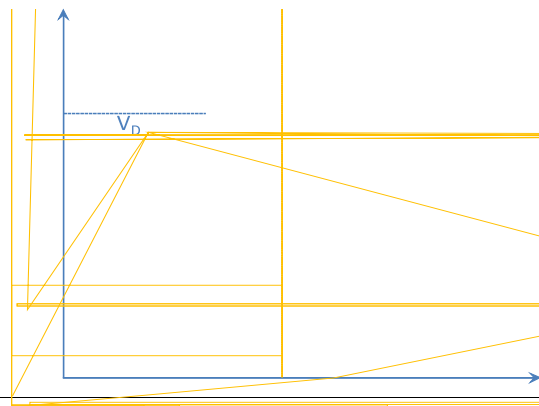
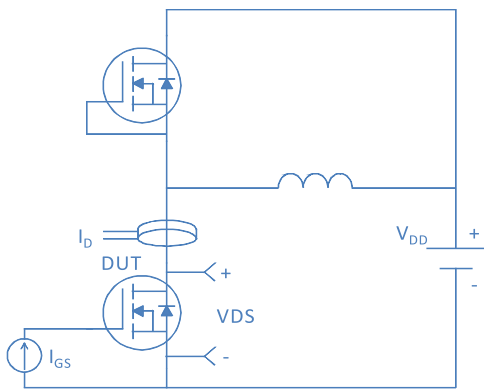
Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case



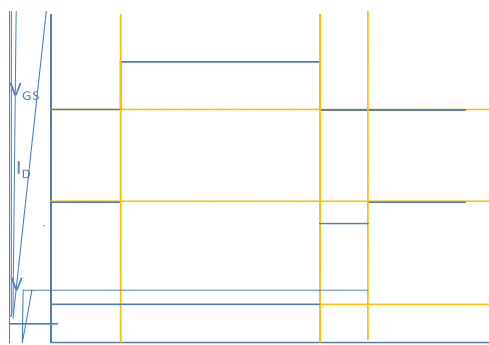
Inductive switching Test



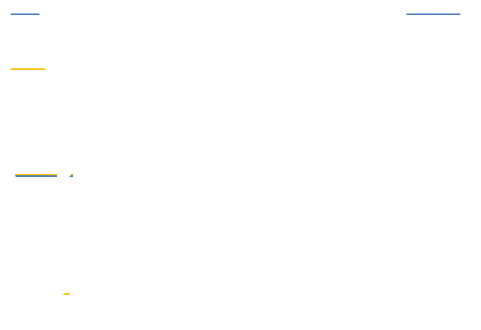
Gate Charge Test



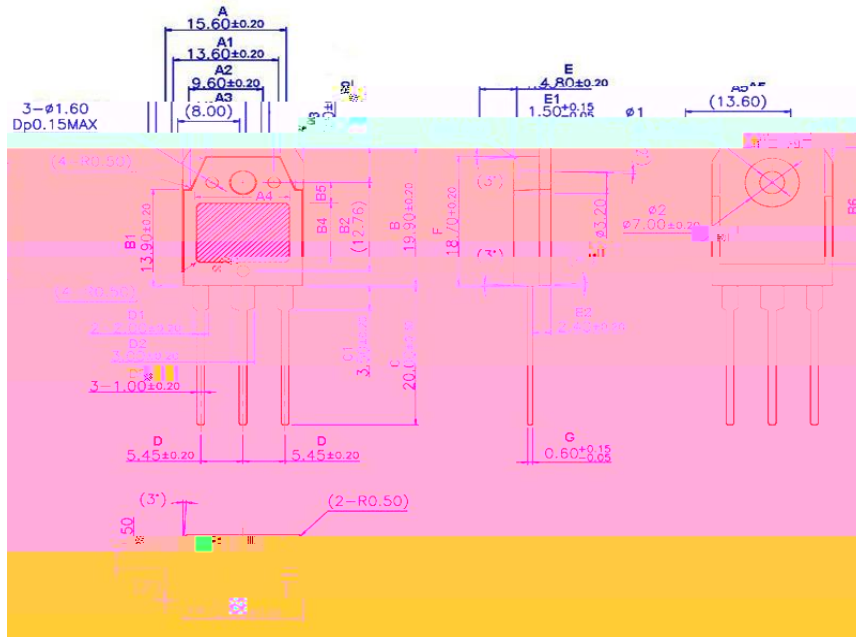
Uclamped Inductive Switching (UIS) Test



Diode Recovery Test



TO-3P, 3 leads



(单位: mm)

符号	尺寸		符号	尺寸		符号	尺寸		符号	尺寸	
	Min	Max		Min	Max		Min	Max		Min	Max
E2	2.20	2.60	A	15.40	15.80	B1	13.70	14.10	C1	3.30	3.70
G	0.55	0.75	A2	9.40	9.80	B3	4.80	5.20	D1	1.80	2.20
Φ1	1.60	1.65	A3	8.00	8.00	B4	12.76	12.76	D2	1.80	1.80
0.80	1.20	Φ2	6.80	7.20	A4	(12.00)	B5	(3.00)	D3		
E	4.60	5.00				A5	(13.60)	B6	(16.76)		
F1	1.45	1.65				B	19.70	20.10	C	19.70	20.30